

Notice of References Cited	Application/Control No. 10/616,525	Applicant(s)/Patent Under Reexamination FUNK ET AL.	
	Examiner J. Derek Rutten	Art Unit 2192	Page 1 of 1

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*	B	US-5,533,192 A	07-1996	Hawley et al.	714/28
*	C	US-5,768,500 A	06-1998	Agrawal et al.	714/47
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NON-PATENT DOCUMENTS

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	V	Rosenberg, "How Debuggers Work", 1996, John Wiley & Sons, Chapters 1-3
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.